

<b>Notice of References Cited</b>	Application/Control No. 09/900,071	Applicant(s)/Patent Under Reexamination BOIS ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,946,482	08-1999	Barford et al.	703/14
	B	US-4,816,767	03-1989	Cannon et al.	324/601
	C	US-6,614,237	09-2003	Ademian et al.	324/601
	D	US-6,643,597	11-2003	Dunsmore, Joel	702/104
	E	US-6,826,506	11-2004	Adamian et al.	702/118
	F	US-6,653,848	11-2003	Adamian et al.	324/638
	G	US-2002/0147575	10-2002	Bois et al.	703/14
	H	US-2004/0193382	09-2004	Adamian et al.	702/118
	I	US-2002/0193977	12-2002	Elco, Richard A.	703/15
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Liao, Haifang, et al. "S-Parameter Based Macro Model of Distributed-Lumped Networks Using Exponentially Decayed Polynomial Function." Proc. 30 <sup>th</sup> Int'l IEEE/ACM DAC. 1993. pp.726-731.
	V	Steer, M.B. et al. "Global Modeling of Spatially Distributed Microwave and Millimeter-Wave Systems." IEEE Transactions on Microwave Theory and Techniques." June 1999. vol.47, Issue 6, pp.830-839.
	W	Mautz, J. et al. "Modal Analysis of Loaded N-Port Scatterers." IEEE Transactions on Antennas and Propagation. Mar. 1973. Vol.21, Issue 2, pp.188-199.
	X	Rautio, J. C. "Synthesis of Lumped Models from N-Port Scattering Parameter Data." IEEE Transactions on Microwave Theory and Techniques. March 1994. vol.42, Issue 3, pp.535-537.

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	A	US-			
	B	US-			
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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lin, Shen et al. "Transient Simulation of Lossy Coupled Transmission Lines." Proc. Conf. on European Design Automation. 1992. pp.126-131.
	V	Sercu, S. et al. "A New Algorithm for Experimental Circuit Modeling of Interconnection Structures Based on Causality." IEEE Transactions on Components, Packaging, and Manuf. Technology. May 1996. Vol.19, Part B, pp.289-295.
	W	Jackson, R.W. "A Circuit Topology for Microwave Modeling of Plastic Surface Mount Packages." IEEE Transactions on Microwave Theory and Techniques. July 1996. vol.44, pp.1140-1146.
	X	Sercu, S. et al. "A New Approach for the Experimental Circuit Modeling of COupled Interconnection Structures Based on Causality." IEEE Transactions on Microwave Theory and Techniques. Oct. 1997. Vol.45, Issue 10, pp.1977-1981.

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.